

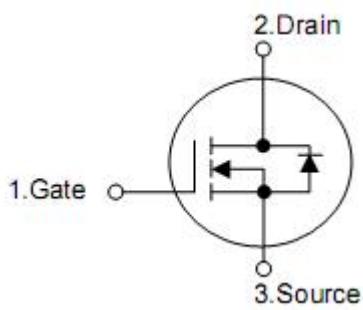
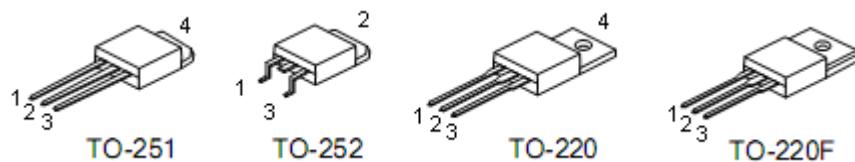
1. Description

The KIA2N60H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

2. Features

- $R_{DS(ON)}=4.1\Omega @ V_{GS}=10V$.
- Low gate charge (typical 9nC)
- High ruggedness
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain

4. Absolute maximum ratings

Parameter		Symbol	Rating			Units
			252/251	220	220F	
Drain-source voltage		V_{DSS}		600		V
Gate-source voltage		V_{GSS}		± 30		V
Drain current continuous	$T_C=25^\circ\text{C}$	I_D	2.0*	2.0	2.0*	A
	$T_C=100^\circ\text{C}$		1.35*	1.35	1.35*	A
Drain current pulsed (note1)		I_{DP}	8*	8	8*	A
Avalanche Enlsed	Repetitive (note1)	E_{AR}		4.4		mJ
	Single pulse (note2)	E_{AS}		120		mJ
Peak diode recovery dv/dt (note3)		dv/dt		4.5		V/ns
Total power dissipation	$T_C=25^\circ\text{C}$	P_D	44	55.5	23.6	W
	Derate above 25°C		0.35	0.44	0.19	W/ $^\circ\text{C}$
Junction temperature		T_J		+150		$^\circ\text{C}$
Storage temperature		T_{STG}		-50~+150		$^\circ\text{C}$

*Drain current limited by maximum junction temperature.

5. Thermal characteristics

Parameter	Symbol	Rating			Unit
		252/251	220	220F	
Thermal resistance,Junction-ambient	R_{thJA}	62.5	62.5	62.5	$^\circ\text{C}/\text{W}$
Thermal resistance,case-to-sink typ.	R_{thCS}	--	0.5	--	$^\circ\text{C}/\text{W}$
Thermal resistance,Junction-case	R_{thJC}	2.87	2.25	5.3	$^\circ\text{C}/\text{W}$

6. Electrical characteristics

($T_C = 25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Off characteristics						
Drain-source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	600	-	-	V
Zero gate voltage drain current	I_{DSS}	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=480\text{V}, T_C=125^\circ\text{C}$	-	-	10	μA
Gate-body leakage current	I_{GSS}	$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA
		$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$	-	0.7	-	V/°C
On characteristics						
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=1.0\text{A}$	-	4.1	5.0	Ω
Dynamic characteristics						
Input capacitance	C_{ISS}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	200	-	pF
Output capacitance	C_{OSS}		-	20	-	pF
Reverse transfer capacitance	C_{RSS}		-	4	-	pF
Switching characteristics						
Turn-on delay time	$t_{\text{D(ON)}}$	$V_{\text{DD}}=300\text{V}, I_{\text{D}}=2.0\text{A}, R_G=25\Omega$ (note4,5)	-	10	-	ns
Rise time	t_R		-	25	-	ns
Turn-off delay time	$t_{\text{D(OFF)}}$		-	25	-	ns
Fall time	t_F		-	30	-	ns
Total gate charge	Q_G	$V_{\text{DS}}=480\text{V}, I_{\text{D}}=2.0\text{A}$ $V_{\text{GS}}=10\text{V}$ (note4,5)	-	9	-	nC
Gate-source charge	Q_{GS}		-	1.5	-	nC
Gate-drain charge	Q_{GD}		-	4.0	-	nC
Drain-source diode characteristics						
drain-source diode forward voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=2.0\text{A}$	-	-	1.4	V
Continuous drain-source current	$I_{\text{SD}*}$		-	-	2.0	A
Pulsed drain-source current	$I_{\text{SM}*}$				8.0	A
Reverse recovery time	t_{RR}	$I_{\text{SD}}=2.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note4)		230	-	ns
Reverse recovery charge	Q_{RR}			1.0	-	μC

Notes: 1. repetitive rating:pulse width limited by maximum junction temperature

2. $L=60\text{mH}, I_{\text{AS}}=2.0\text{A}, V_{\text{DD}}=50\text{V}, R_G=25\Omega$, starting $T_J=25^\circ\text{C}$

3. $I_{\text{SD}} \leq 2.0\text{A}, dI/dt \leq 200\text{A}/\mu\text{s}, V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$, starting $T_J=25^\circ\text{C}$

4. Pulse test:pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$

5. Essentially independent of operating temperature

7. Typical characteristics

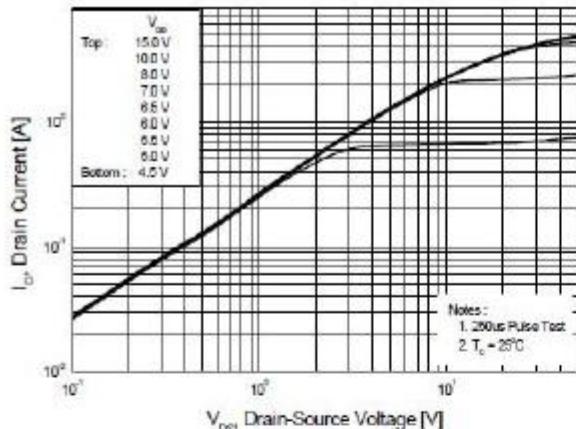


Figure 1. On-Region Characteristics

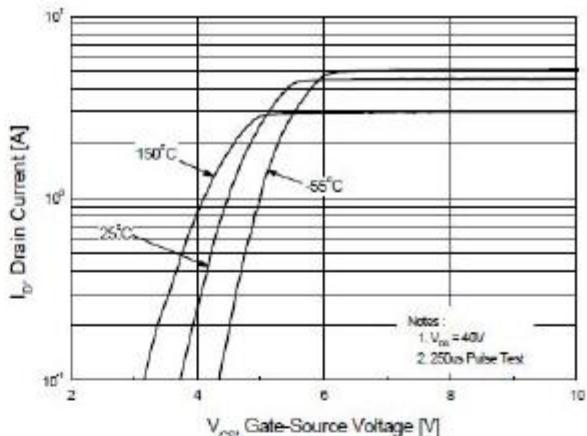


Figure 2. Transfer Characteristics

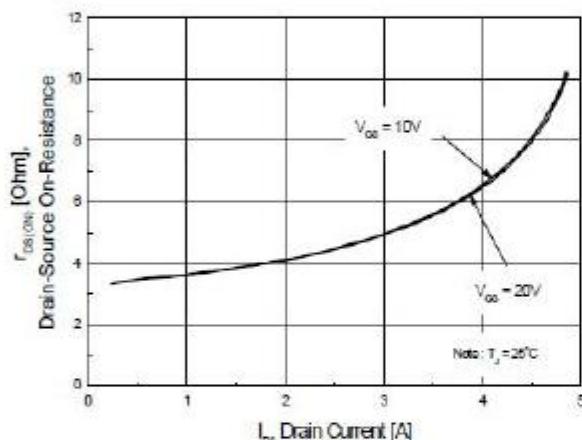


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

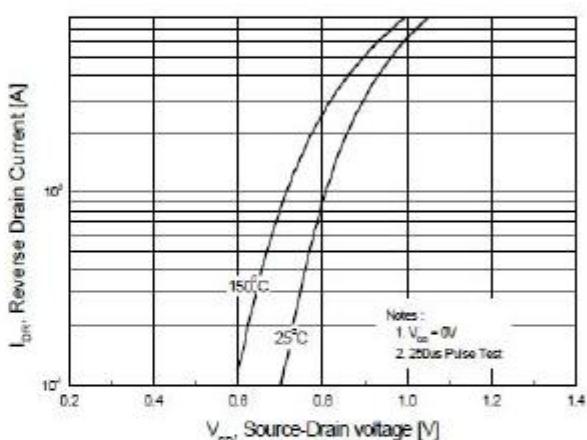


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

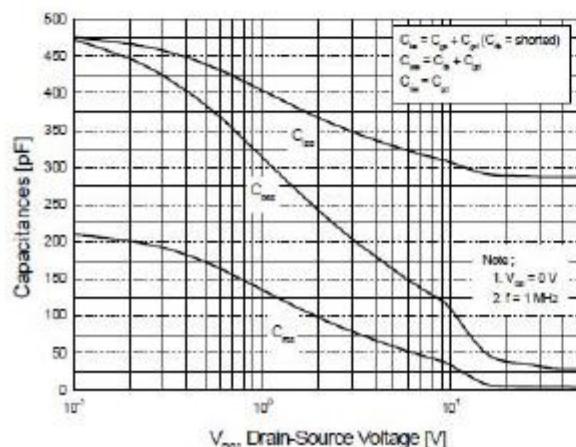


Figure 5. Capacitance Characteristics

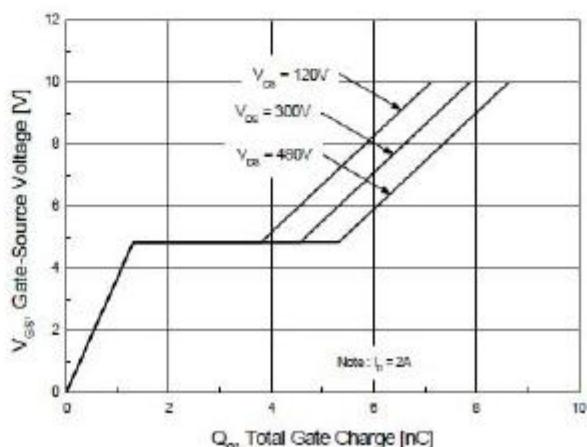


Figure 6. Gate Charge Characteristics

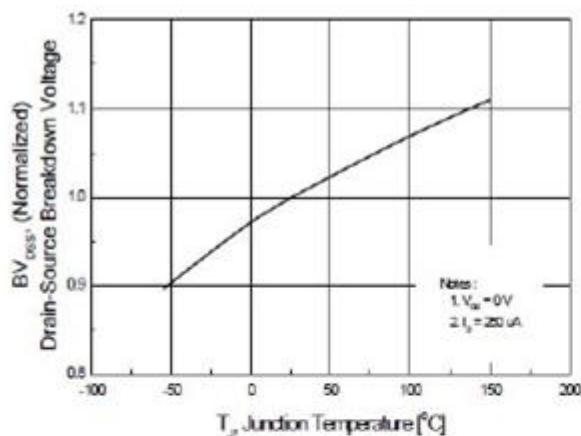


Figure 7. Breakdown Voltage Variation vs Temperature

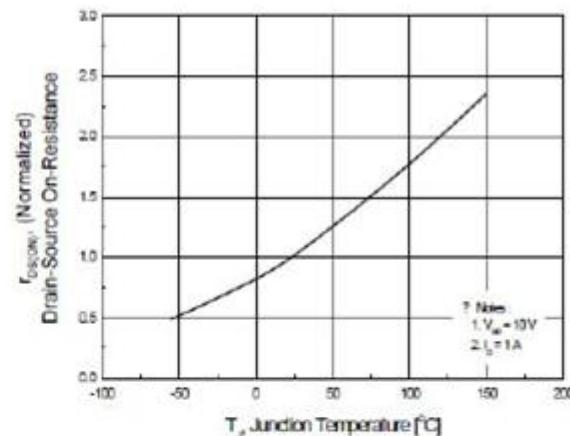


Figure 8. On-Resistance Variation vs Temperature

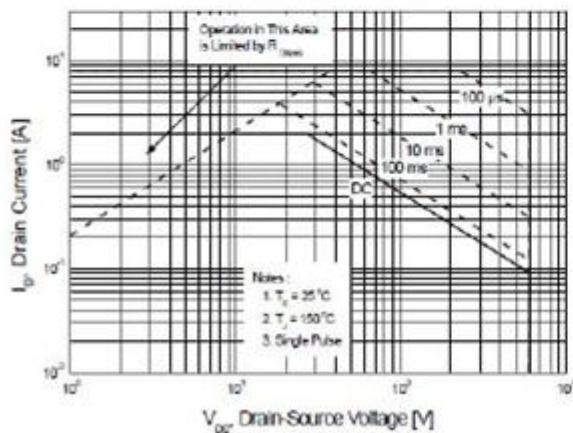


Figure 9 . Maximum Safe Operating Area

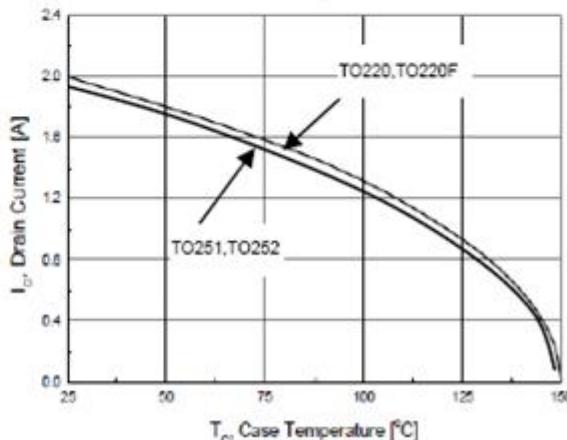


Figure 10. Maximum Drain Current vs Case Temperature

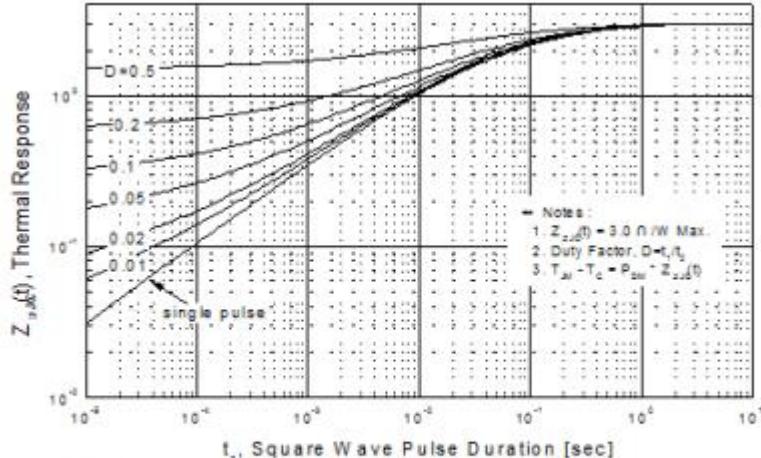
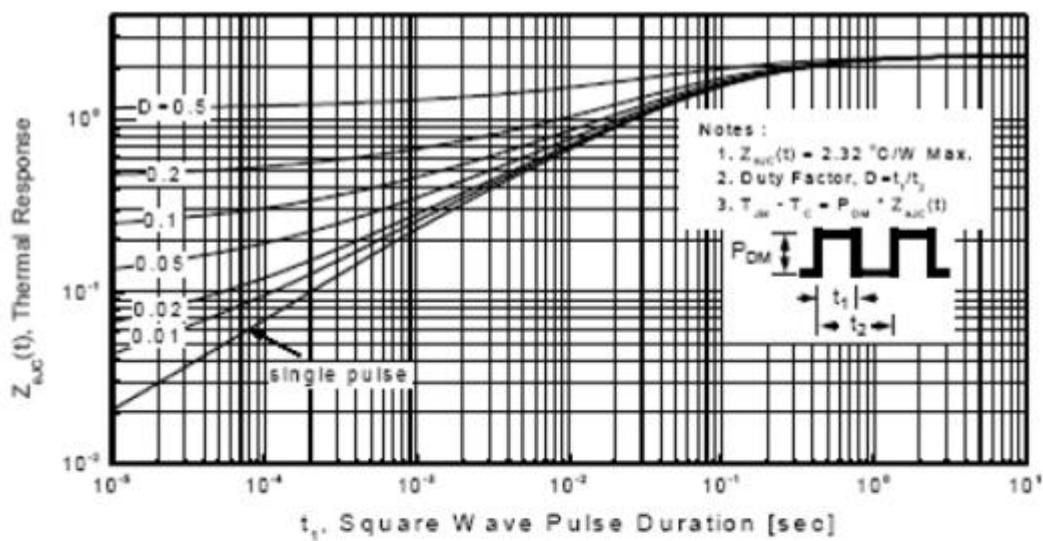
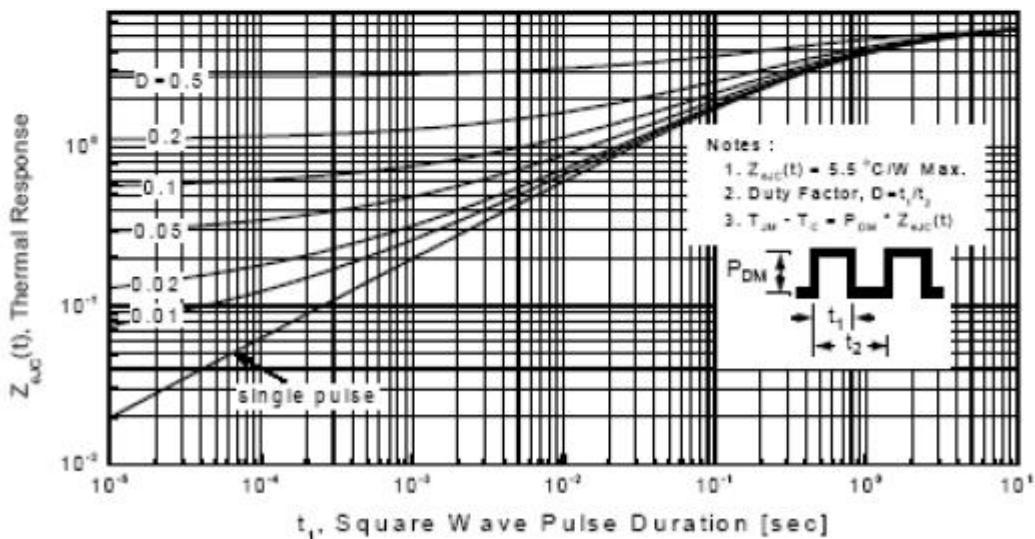


Figure 11. Transient Thermal Response Curve for TO-251/252



**Figure 11-1. Transient Thermal Response Curve
for TO-220**



**Figure 11-2. Transient Thermal Response Curve
for TO-220F**